


<b>Search Notes</b>  	<b>Application/Control No.</b>  10637223	<b>Applicant(s)/Patent Under Reexamination</b>  LIU, ZICHENG
	<b>Examiner</b>  Chawan, Sheela C	<b>Art Unit</b>  2624

SEARCHED			
Class	Subclass	Date	Examiner
382	118,154,276	3/2/07	SCC
345	473,646	"	"
700	98	"	"
703	2	"	"
ABOVE SEARCH UP-DATE.		"	"

SEARCH NOTES		
Search Notes	Date	Examiner
EAST, US-PGPUB, USPAT, EPO,JPO,DERWENT, IBM-TDB, SEE ATTACHED SEARCH HISTORY	3/2/07	SCC
382/ 118,154, 276. US-PATENT ONLY SEE TEXT SEARCH.,	"	"
345/419, 420, 473,426,646. CCLS. "	"	"
700/98.CCLS. "	"	"
703/2.CCLS. "	"	"
INTERFERENCE SEARCH , SEE SEARCH HISTORY PRINT OUT.	"	"
INVENTOR NAME SEARCH.	"	"
IEEE OR INSPEC DATABASE SEARCH.	"	"
ABOVE SEARCH UP- DATE.	"	"

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
382	118,154,276	3/2/07	SCC
345	473,646	"	"
700	98	"	"
703	2	"	"